

# Yasuhiko Imai

## List of Publications by Year in descending order

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Version: 2024-02-01

32  
papers

568  
citations

933447

10  
h-index

610901

24  
g-index

32  
all docs

32  
docs citations

32  
times ranked

1068  
citing authors

#	ARTICLE	IF	CITATIONS
1	Impact of mechanical stress on ferroelectricity in (Hf <sub>0.5</sub> Zr <sub>0.5</sub> )O <sub>2</sub> thin films. Applied Physics Letters, 2016, 108, .	3.3	187
2	Controlling charge-density-wave states in nano-thick crystals of 1T-TaS <sub>2</sub> . Scientific Reports, 2014, 4, 7302.	3.3	126
3	Effect of the film thickness on the crystal structure and ferroelectric properties of (Hf <sub>0.5</sub> Zr <sub>0.5</sub> )O <sub>2</sub> thin films deposited on various substrates. Materials Science in Semiconductor Processing, 2017, 70, 239-245.	4.0	41
4	High-Angular-Resolution Microbeam X-Ray Diffraction with CCD Detector. AIP Conference Proceedings, 2010, , .	0.4	25
5	Extended Polymorphism of Two-Dimensional Material. Nano Letters, 2017, 17, 5567-5571.	9.1	25
6	In-situ observation of ultrafast 90° domain switching under application of an electric field in (100)/(001)-oriented tetragonal epitaxial Pb(Zr <sub>0.4</sub> Ti <sub>0.6</sub> )O <sub>3</sub> thin films. Scientific Reports, 2017, 7, 9641.	3.3	23
7	Fabrication of tensile-strained single-crystalline GeSn on transparent substrate by nucleation-controlled liquid-phase crystallization. Applied Physics Letters, 2017, 110, .	3.3	16
8	Electric-Field-Driven Nanosecond Ferroelastic-Domain Switching Dynamics in Epitaxial $\text{Pb}(\text{Zr}_{0.4}\text{Ti}_{0.6})\text{O}_3$ Thin Films. <i>ACS Applied Materials &amp; Interfaces</i> , 2017, 9, 1511-1518.	7.8	16
9	57Fe polarization-dependent synchrotron Mössbauer spectroscopy using a diamond phase plate and an iron borate nuclear Bragg monochromator. Journal of Synchrotron Radiation, 2015, 22, 427-435.	2.4	11
10	Large irreversible non-180° domain switching after poling treatment in Pb(Zr, Ti)O <sub>3</sub> films. Applied Physics Letters, 2016, 108, .	3.3	10
11	Quantification of local strain distributions in nanoscale strained SiGe FinFET structures. Journal of Applied Physics, 2017, 122, .	2.5	9
12	Characterization of domain structure in one-dimensional SrRuO <sub>3</sub> nanostructure using synchrotron x-ray microdiffraction. AIP Conference Proceedings, 2016, , .	0.4	8
13	Parabolic refractive X-ray lenses made of quartz glass for high-energy X-ray focusing. Japanese Journal of Applied Physics, 2016, 55, 038001.	1.5	7
14	Nanometer-Scale Characterization Technique for Si Nanoelectric Materials Using Synchrotron Radiation Microdiffraction. Key Engineering Materials, 2011, 470, 104-109.	0.4	6
15	Crystalline property analysis of semipolar (20°±21) GaN on (22°±43) patterned sapphire substrate by X-ray microdiffraction and transmission electron microscopy. Physica Status Solidi (B): Basic Research, 2015, 252, 1149-1154.	1.5	6
16	Microstructural analysis of an epitaxial AlN thick film/trench-patterned template by three-dimensional reciprocal lattice space mapping technique. Applied Physics Express, 2016, 9, 111001.	2.4	6
17	Tomographic Mapping Analysis in the Depth Direction of High-Ge-Content SiGe Layers with Compositionally Graded Buffers Using Nanobeam X-ray Diffraction. ACS Applied Materials & Interfaces, 2017, 9, 13726-13732.	8.0	6
18	Stroboscopic topographies on iron borate crystal in 9.6 MHz rf magnetic field. Nuclear Instruments & Methods in Physics Research B, 2003, 199, 75-80.	1.4	4

